

**INTERNATIONAL
STANDARD**

**IEC
60068-2-69**

Second edition
2007-05

Environmental testing –

Part 2-69:

**Tests – Test Te: Solderability testing of electronic
components for surface mounting devices (SMD)
by the wetting balance method**



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CONTENTS

FOREWORD.....	3
1 Scope.....	5
2 Normative references	5
3 Terms and definitions	6
4 General description of the method.....	6
5 Description of the test apparatus	6
6 Preconditioning.....	7
6.1 Preparation of specimens.....	7
6.2 Ageing.....	7
7 Materials	7
7.1 Solder	7
7.2 Flux.....	8
8 Procedures.....	8
8.1 Test temperature.....	8
8.2 Solder bath wetting balance procedure.....	8
8.3 Solder globule wetting balance procedure	11
9 Presentation of results.....	14
9.1 Form of force versus time trace.....	14
9.2 Test requirements	15
10 Information to be given in the relevant specification	15
Annex A (normative) Equipment specification	16
Annex B (informative) Use of the wetting balance for SMD solderability testing	18
Bibliography.....	25
Figure 1 – Test apparatus.....	6
Figure 2 – Typical wetting balance trace	14
Table 1 – Recommended solder bath wetting balance test conditions	10
Table 2 – Time sequence of the test (solder bath)	11
Table 3 – Recommended solder globule wetting balance test conditions.....	12
Table 4 – Time sequence of the test (Solder globule)	13

INTERNATIONAL ELECTROTECHNICAL COMMISSION

ENVIRONMENTAL TESTING –

**Part 2-69: Tests –
Test Te: Solderability testing of electronic
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International Standard IEC 60068-2-69 has been prepared by IEC technical committee 91: Electronics assembly technology.

This second edition cancels and replaces the first edition published in 1995 and constitutes a technical revision. The main changes from the previous edition are as follows:

- Inclusion of lead-free alloy test conditions;
- Inclusion of new fluxes for testing, reflecting development of fluxes that have happened in the industry in the past 20 years;
- Inclusion of new component types, and updating test parameters for the whole component list.

The text of this standard is based on the following documents:

FDIS	Report on voting
91/648/FDIS	91/680/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

A list of all the parts in the IEC 60068 series, under the general title *Environmental testing*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the maintenance result date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

ENVIRONMENTAL TESTING –

Part 2-69: Tests – Test Te: Solderability testing of electronic components for surface mounting devices (SMD) by the wetting balance method

1 Scope

This part of IEC 60068 outlines test Te, solder bath wetting balance method and solder globule wetting balance method, applicable for surface mounting devices. These methods determine quantitatively the solderability of terminations on surface mounting devices. IEC 60068-2-54 is also available for surface mounting devices and should be consulted if applicable.

The procedures describe the solder bath wetting balance method and the solder globule wetting balance method and are both applicable to components with metallic terminations and metallized solder pads.

This standard provides the standard procedures for solder alloys containing lead (Pb) and for lead-free solder alloys.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60068-1, *Environmental testing – Part 1: General and guidance*

IEC 60068-2-20:1979, *Basic environmental testing procedures – Part 2: Tests – Test T: Soldering*
Amendment 2 (1987)

IEC 60068-2-54:2006, *Environmental testing – Part 2-54: Tests – Test Ta: Solderability testing of electronic components by the wetting balance method*

IEC 61190-1-3:2002, *Attachment materials for electronic assemblies – Part 1-3: Requirements for electronic grade solder alloys and fluxed/non-fluxed solid solder for electronic soldering applications*

ISO 683 (all parts), *Heat-treatable steels, alloy steels and free-cutting steels*

ISO 6362 (all parts), *Wrought aluminium and aluminium alloy extruded rods/bars, tubes and profiles*